ABBREVIATIONS

AFM: Atomic force microscopy
CB: Conduction band
CBD: Chemical bath deposition
EDAX: Energy dispersive analysis by X-rays
JCPDS: Joint committee on powder diffraction standard
LEL: Lower explosive limit
LVDT: Linear variable differential transformer
MOS: Metal oxide semiconductor
OPCW: Organization for prohibition of chemical weapons
RF: Radio frequency
RFMS: Radio frequency magnetron sputtering
RT: Room temperature
SAED: Selected area electron diffraction
SEM: Scanning electron microscopy
SPT: Spray pyrolysis technique
TEM: Transmission electron microscopy
TIC: Toxic industrial chemicals
UV: Ultra violet
VB: Valence band
XRD: X-ray diffraction